

National Institute of Technology, Agartala Barjala, Jirania, West Tripura-799046

CENTRAL RESEARCH FACILITY

SAMPLE REQUISITION FROM FOR ATOMIC FORCE MICROSCOPY FACILITY

Application No: NITA/CRF/AFM	/ Slot Tim	ne: Slot Da	te:/
User Information			Candidate: Internal/External
Department: Contact No:	Branch:	Course:	
E-mail address:Contact Address (For External Us			
*Internal candidates represent the student's/Staff/Faculty members belong to NIT Agartala.			
Instruction 1. No loose powders, corrosive sa 2. One sample will roughly take 3 samples will be done if materials 3. Please do not bring very rough 4. Maximum samples thickness 3 5. Maximum samples dimension 8 6. Normally imaging in intermitte imaging. 7. Please do not bring samples we not touch sample with hand.	0 mins for imaging. Maximum th are different materials. (roughness ~ 1 micron or higher mm. 8×8 mm 2. nt contact mode (trapping mode	ree samples (same material) willb	ve to wait for contact mode
Sample Description			
Sample Description Sample Number	Sample-1	Sample-2	Sample-3
What are you trying to see?	,		·
Expected feature size			
-	knowledge and belief, failure w	hich my application may be termi	at the above information furnished inated for future use. Furthermore I vided.
Signature (Student/Scholar)	•	e with stamp sor/Guide/PI)	Signature with stamp (HOD)
	n No:	Dated:	
Acc. Name: NIT Agartala - Project IFSC Code: SBIN0011491			plication form) IT Agartala (011491)
For Office Use			
The user may be allowed to use t (Any other comments)	he facility as per the procedure.		Faculty in Charge, CRF, NITA
			,
			Chairman, CRF, NITA